eGaN® FET DATASHEET EPC2934C

## **EPC2934C – Enhancement Mode Power Transistor**

 $V_{DS}$  , 200 V  $R_{DS(on)} \; , \; 8 \; m\Omega$   $I_D \; , \; 39 \; A \\ 95\% \; Pb/5\% \; Sn \; Solder$ 







Revised February 22, 2024

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.





	Maximum Ratings				
	PARAMETER VALUE UNIT				
$V_{DS}$	Drain-to-Source Voltage (Continuous)	200	V		
	Continuous ( $T_A = 25$ °C, $R_{\theta JA} = 9$ °C/W)	39	۸		
l <sub>D</sub>	Pulsed (25°C, $T_{PULSE} = 300 \mu s$ )	213	Α		
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	Gate-to-Source Voltage	6	V		
$V_{GS}$	Gate-to-Source Voltage	-4			
TJ	Operating Temperature	-40 to 150	- °C		
T <sub>STG</sub>	Storage Temperature	-55 to 150	C		

Thermal Characteristics				
	PARAMETER	ТҮР	UNIT	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.3		
R <sub>OJB</sub> Thermal Resistance, Junction-to-Board 4 °C		°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	45		

Note 1:  $R_{\theta,A}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details.

	Static Characteristics ( $T_j = 25^{\circ}$ C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV <sub>DSS</sub>	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 0.6 \text{ mA}$	200			V
I <sub>DSS</sub>	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 160 \text{ V}$		0.03	0.4	
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.002	4	mA
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.03	0.4	
V <sub>GS(TH)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 7 \text{ mA}$	0.8	1.1	2.5	V
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_D = 20 \text{ A}$		6	8	mΩ
$V_{SD}$	Source-Drain Forward Voltage#	$V_{GS} = 0 \text{ V, } I_S = 0.5 \text{ A}$		1.7		V

# Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.



Die size: 4.6 x 2.6 mm

**EPC2934C** eGaN® FETs are supplied only in passivated die form with solder bumps.

## **Applications**

- · High speed DC-DC conversion
- · Motor drive
- · Industrial automation
- · Synchronous rectification
- · Class-D audio

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2934C

EPC2934C eGaN® FET DATASHEET

Dynamic Characteristics# (T <sub>J</sub> = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance			1155	1386	
C <sub>RSS</sub>	Reverse Transfer Capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V}$		3.1		
Coss	Output Capacitance			641	962	pF
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V 0VV 0+-100V		755		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 100 \text{ V}$		969		
$R_{G}$	Gate Resistance			0.5		Ω
$Q_{G}$	Total Gate Charge	$V_{GS} = 5 \text{ V}, V_{DS} = 100 \text{ V}, I_D = 20 \text{ A}$		11.1	13.8	
Q <sub>GS</sub>	Gate-to-Source Charge			3.8		
$Q_{GD}$	Gate-to-Drain Charge	$V_{DS} = 100 \text{ V}, I_D = 20 \text{ A}$		2		
Q <sub>G(TH)</sub>	Gate Charge at Threshold	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V 96 144		nC		
Qoss	Output Charge			144		
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

<sup>#</sup> Defined by design. Not subject to production test.

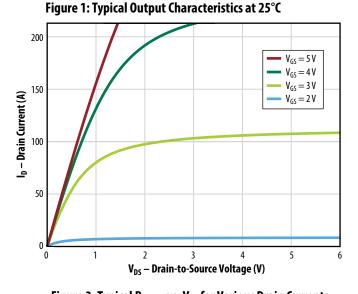
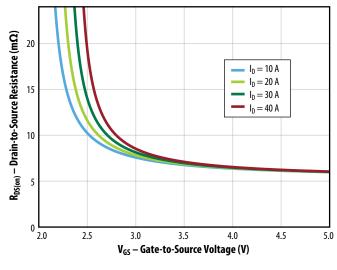


Figure 3: Typical  $R_{\text{DS(on)}}\,\text{vs.}\,V_{\text{GS}}$  for Various Drain Currents



**Figure 2: Typical Transfer Characteristics** 

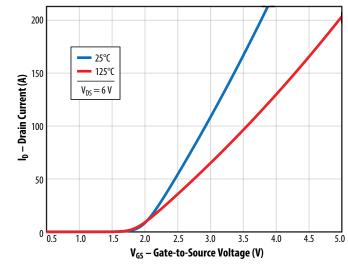
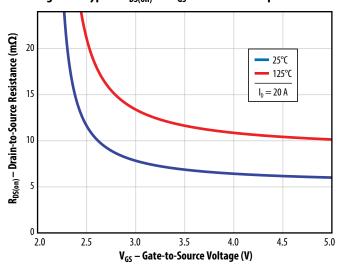


Figure 4: Typical  $R_{DS(on)}\, vs.\, V_{GS}$  for Various Temperatures



All measurements were done with substrate connected to source. Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>. Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.

eGaN® FET DATASHEET EPC2934C

Figure 5a: Typical Capacitance (Linear Scale)

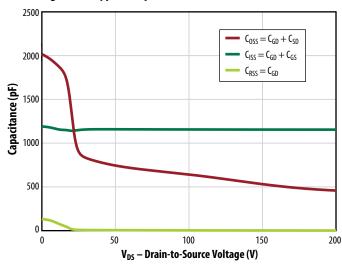


Figure 5b: Typical Capacitance (Log Scale)

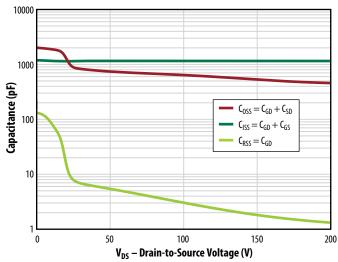


Figure 6: Typical Output Charge and Coss Stored Energy

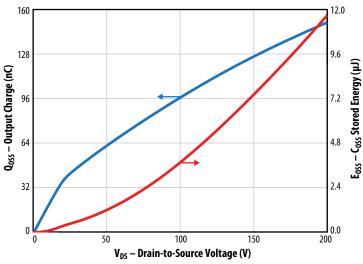
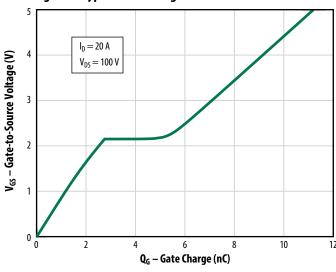


Figure 7: Typical Gate Charge



**Figure 8: Typical Reverse Drain-Source Characteristics** 

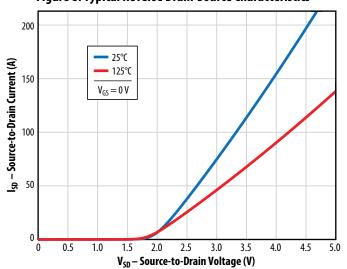
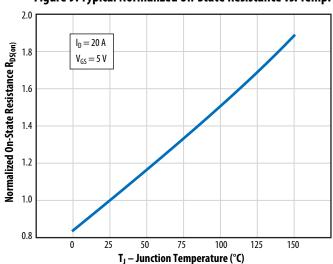


Figure 9: Typical Normalized On-State Resistance vs. Temp.



**Note:** Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

eGaN® FET DATASHEET EPC2934C

 $\label{thm:continuous} \textbf{Figure 10: Typical Normalized Threshold Voltage vs. Temp.}$ 

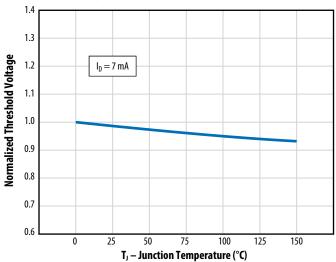
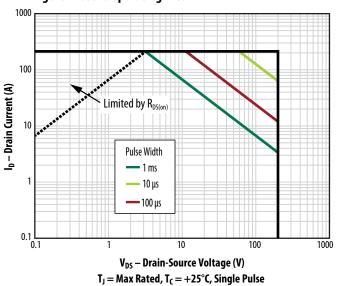
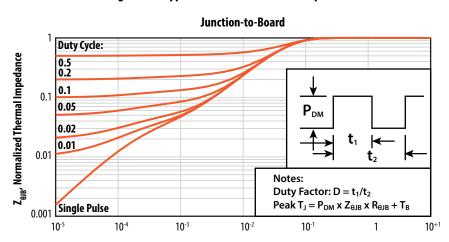


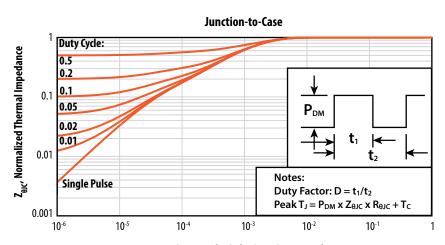
Figure 11: Safe Operating Area



**Figure 12: Typical Transient Thermal Response Curves** 



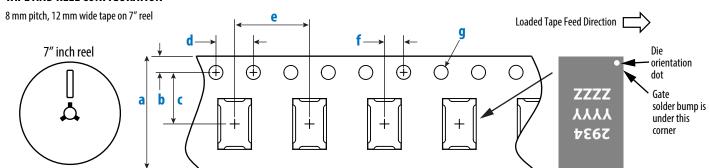
t<sub>1</sub>, Rectangular Pulse Duration, seconds



t<sub>1</sub>, Rectangular Pulse Duration, seconds

EPC2934C eGaN® FET DATASHEET

## **TAPE AND REEL CONFIGURATION**

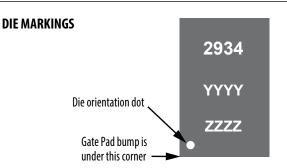


	Dimension (mm)		
EPC2934C (Note 1)	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
<b>c</b> (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
<b>f</b> (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

Die is placed into pocket solder bump side down (face side down)

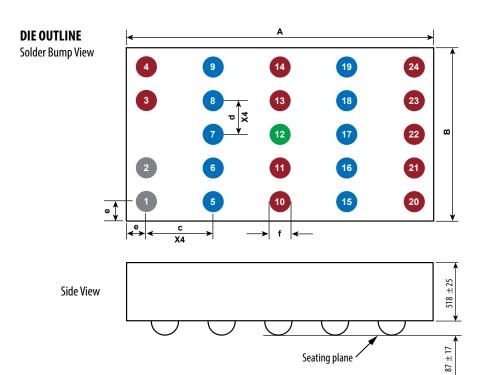
Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.



D- ut	Laser Markings			
Part Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3	
EPC2934C	2934	YYYY	ZZZZ	

eGaN® FET DATASHEET **EPC2934C** 



DIM	Micrometers			
	MIN	Nominal	MAX	
A	4570	4600	4630	
В	2570	2600	2630	
C		1000		
d		500		
e		300		
f		316		

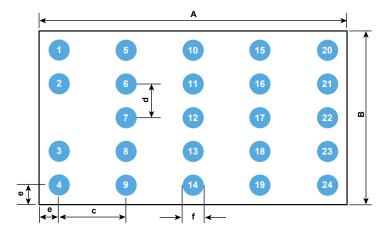
Pads 1 and 2 are Gate;

Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source; Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain; Pad 12 is Substrate\*

\*Substrate pin should be connected to Source

## **RECOMMENDED LAND PATTERN**

(units in  $\mu$ m)



Land pattern is solder mask defined.

DIM	Micrometers
A	4600
В	2600
C	1000
d	500
e	300
f	316

Pads 1 and 2 are Gate;

Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;

Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;

Pad 12 is Substrate\*

\*Substrate pin should be connected to Source

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others. eGaN® is a registered trademark of Efficient Power Conversion Corporation.

EPC Patent Listing: https://epc-co.com/epc/about-epc/patents

Information subject to change without notice.